Notice of References Cited Application/Control No. O9/904,200 Examiner David M. Naff Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,686,184	02-2004	Anderson et al.	435/174
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			_
	Н	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
0	R					
	S					
	Т					

NON-PATENT DOCUMENTS

TOTAL ATENT DOGGILLATO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.